

Notice of References Cited	Application/Control No. 10/709,293	Applicant(s)/Patent Under Reexamination ALLEN ET AL.	
	Examiner Suchin Parihar	Art Unit 2825	Page 1 of 1

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*	D	US-2005/0021234	01-2005	Han, Dianli	702/013
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NON-PATENT DOCUMENTS

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	W	E. Papadopoulou, D.T. Lee, "Critical Area Computation - A new Approach", Proc. International Symposium on Physical Design, April 1998, 89-94.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.